

Notice of References Cited	Application/Control No. 10/777,918		Applicant(s)/Patent Under Reexamination D'HERS ET AL.	
	Examiner SCOTT L. JARRETT		Art Unit 3624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,161,103	12-2000	Rauer et al.	707/4
*	B	US-6,282,544	08-2001	Tse et al.	707/101
*	C	US-6,732,115	05-2004	Shah et al.	707/102
*	D	US-6,385,604	05-2002	Bakalash et al.	707/3
*	E	US-7,139,766	11-2006	Thomson et al.	707/101
*	F	US-7,315,849	01-2008	Bakalash et al.	707/2
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Kimball, Ralph et al., The Data Warehouse Toolkit: The Complete Guide to Dimensional Modeling - Second Edition Wiley Computer Publishing, 2002 ISBN 0-471-20024-7			
*	V	Netz, Amir, OLAP Services: Semiadditive Measures and Inventory Snapshots Microsoft Corporation MSDN, April 1, 1999			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.